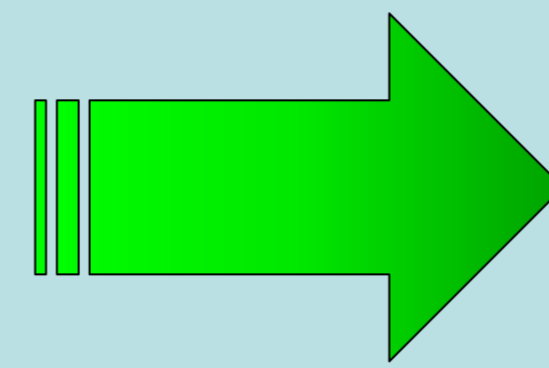


Goal: Transform Test features into product Differentiators



Enhance Access and Control  
Self-repair solutions  
Self-calibration functions



To the integrators  
To end-users

Major Achievement: Wireless Test Access \* 

SiP-SoC  
Production  
Test

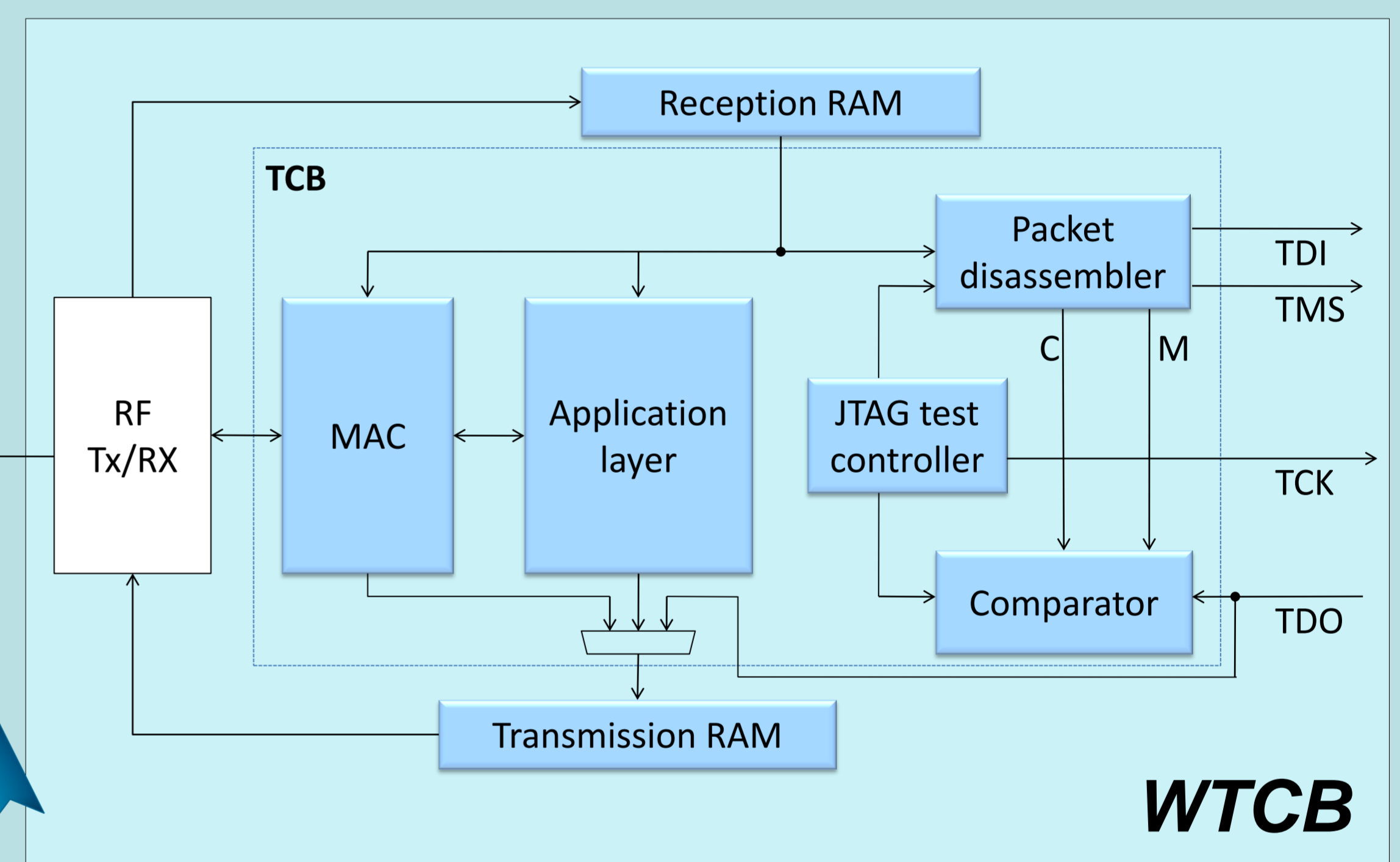


Specific MAC layer: low power, minimal area overhead, reliability

- ✓ Embedded Wireless Test Control Block (WTCB)
- ✓ Test management at circuit level
- ✓ Generic test access

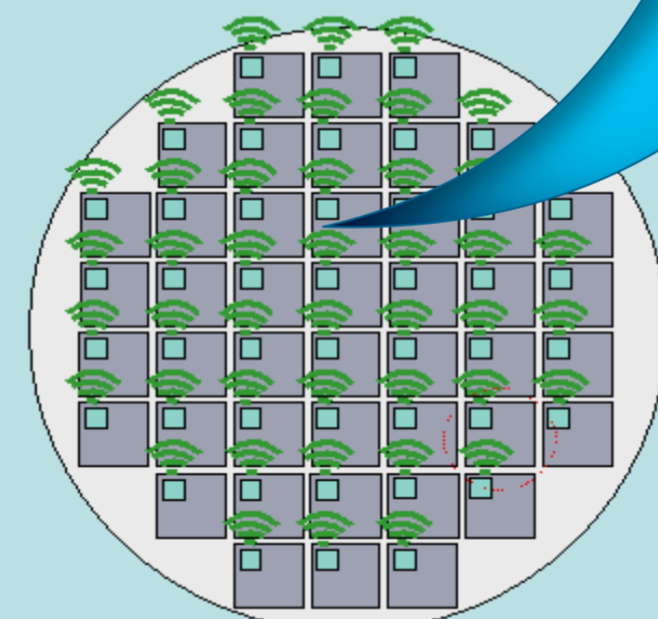
Adaptive Test Response Handling

- ✓ Centralized Comparison on ATE for full diagnostic
- ✓ Distributed Comparison on DUTs for test time reduction



Massive parallel test

➔ Test time reduction by 4-5



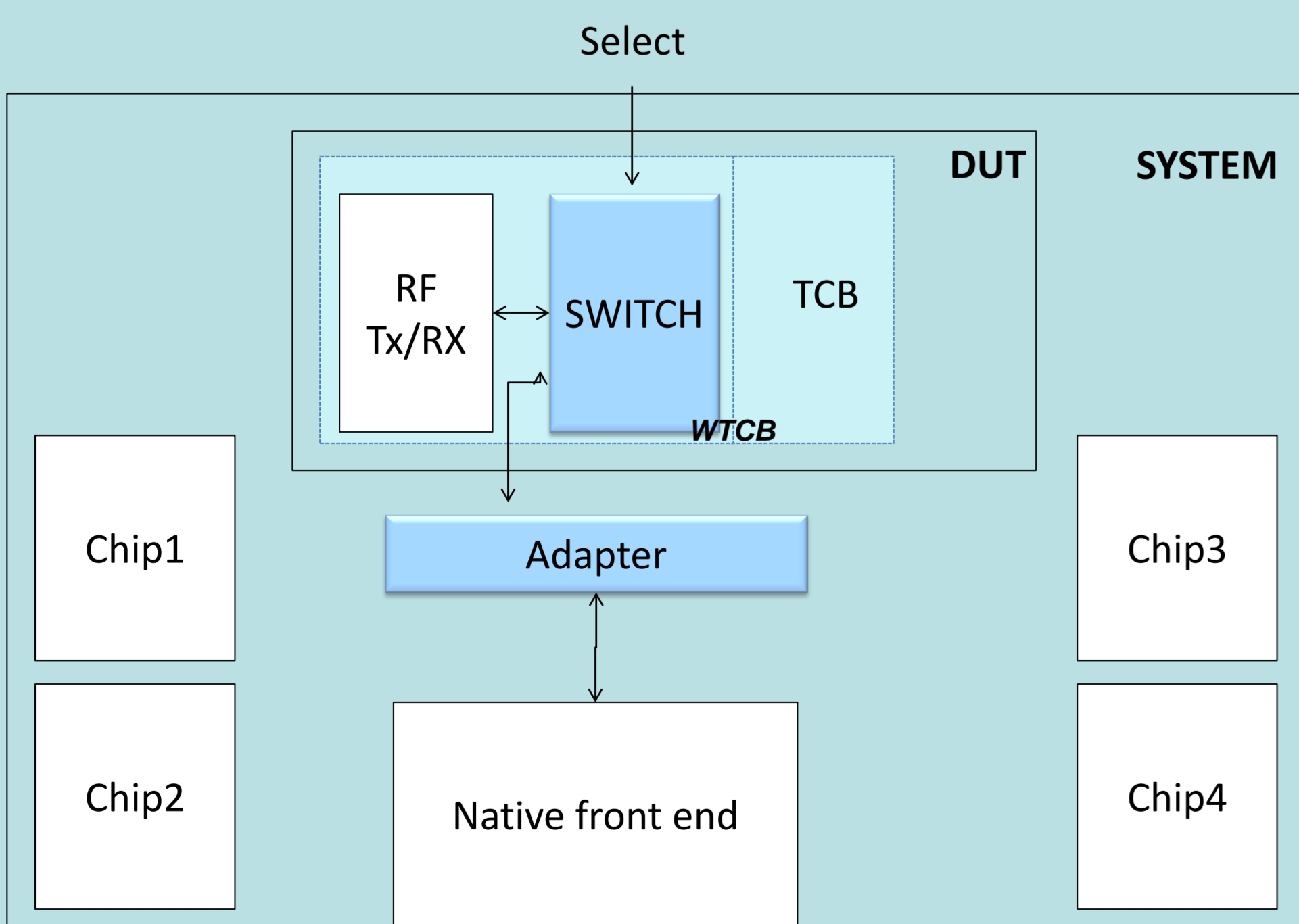
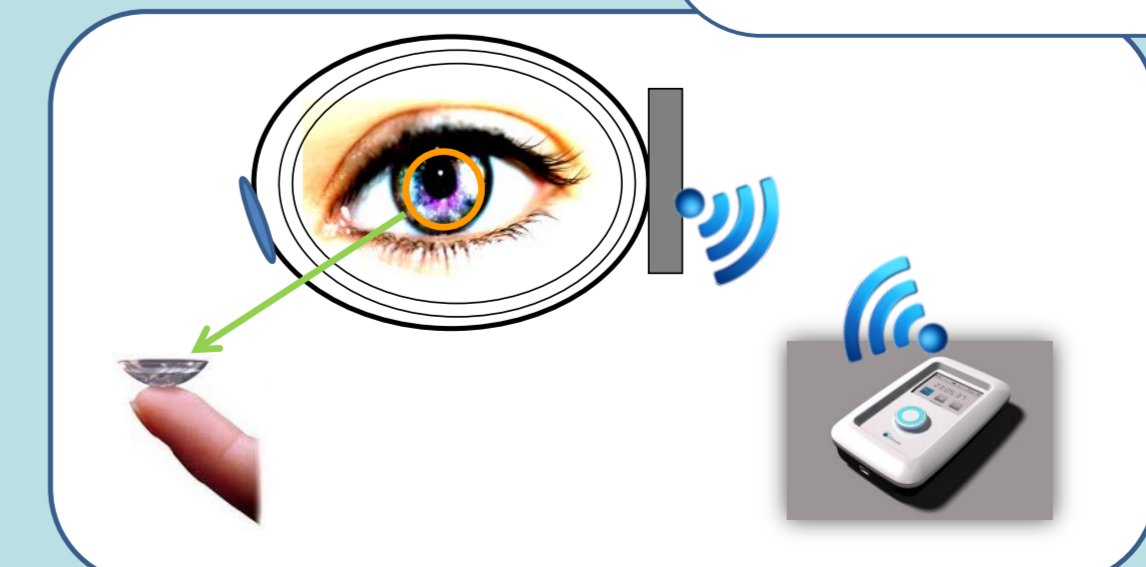
In-Situ  
Test

In Situ/On-line Tests & Diagnostics

- ✓ Easy maintenance
- ✓ Low cost diagnosis

Switch

- ✓ Reuse native wireless frontend
- ✓ Minimal area overhead



\* Works conducted by LIRMM and Optimalia